

Gate Turn-off Thyristor

Replaces March 1998 version, DS4095-5.3

DS4095-6.0 January 2000

APPLICATIONS

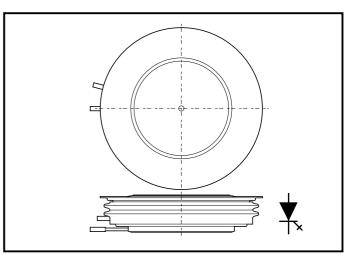
- Variable speed A.C. motor drive inverters (VSD-AC).
- Uninterruptable Power Supplies
- High Voltage Converters.
- Choppers.
- Welding.
- Induction Heating.
- DC/DC Converters.

FEATURES

- Double Side Cooling.
- High Reliability In Service.
- High Voltage Capability.
- Fault Protection Without Fuses.
- High Surge Current Capability.
- Turn-off Capability Allows Reduction In Equipment Size And Weight. Low Noise Emission Reduces Acoustic Cladding Necessary For Environmental Requirements.

$\begin{array}{lll} I_{TCM} & 3000A \\ V_{DRM} & 4500V \\ I_{T(AV)} & 870A \\ dV_{D}/dt & 1000V/\mu s \\ di_{J}/dt & 300A/\mu s \end{array}$

KEY PARAMETERS



Outline type code: X.
See Package Details for further information.

VOLTAGE RATINGS

Type Number	Repetitive Peak Off-state Voltage V _{DRM} V	Repetitive Peak Reverse Voltage V _{RRM} V	Conditions
DG758BX45	4500	16	$T_{v_j} = 125^{\circ}C, I_{DM} = 100mA,$ $I_{RRM} = 50mA$

CURRENT RATINGS

Symbol	Parameter	Conditions	Max.	Units
I _{TCM}	Repetitive peak controllable on-state current	$V_D = 66\% V_{DRM}, T_j = 125^{\circ}C, di_{GQ}/dt = 40A/\mu s, Cs = 6\mu F$	3000	Α
I _{T(AV)}	Mean on-state current	T _{HS} = 80°C. Double side cooled. Half sine 50Hz.	870	Α
I _{T(RMS)}	RMS on-state current	$T_{HS} = 80^{\circ}C$. Double side cooled. Half sine 50Hz.	1365	Α

SURGE RATINGS

Symbol	Parameter	Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine. T _j = 125°C	16.0	kA
l²t	I ² t for fusing	10ms half sine. T _j =125°C	1.28 x 10 ⁶	A²s
di _T /dt	Critical rate of rise of on-state current	$V_{_{D}} = 3000 \text{V}, I_{_{T}} = 3000 \text{A}, T_{_{j}} = 125 ^{\circ}\text{C}, I_{_{FG}} > 40 \text{A},$ Rise time > 1.0 μ s	300	A/μs
al\	Data of vice of off state vallence	To 66% V_{DRM} ; $R_{GK} \le 1.5Ω$, $T_j = 125°C$	100	V/μs
dV _D /dt	Rate of rise of off-state voltage	To 66% V _{DRM} ; V _{RG} = -2V, T _j = 125°C	1000	V/µs
L _s	Peak stray inductance in snubber circuit	-	200	nH

GATE RATINGS

Symbol	Parameter	Parameter Conditions		Max.	Units
V _{RGM}	Peak reverse gate voltage	This value maybe exceeded during turn-off	-	16	V
I _{FGM}	Peak forward gate current		-	100	А
P _{FG(AV)}	Average forward gate power		-	20	W
P _{RGM}	Peak reverse gate power		-	24	kW
di _{GQ} /dt	Rate of rise of reverse gate current		30	60	A/μs
t _{ON(min)}	Minimum permissable on time		50	-	μs
t _{OFF(min)}	Minimum permissable off time		100	-	μs

THERMAL RATINGS AND MECHANICAL DATA

Symbol	Parameter	Conditions		Min.	Max.	Units
$R_{th(j-hs)}$	DC thermal resistance - junction to heatsink surface	Double side cooled		-	0.0146	°C/W
		Anode side cooled		-	0.0233	°C/W
		Cathode side cooled		-	0.0392	°C/W
$\boldsymbol{R}_{\text{th(c-hs)}}$	Contact thermal resistance	Clamping force 35.0kN With mounting compound	per contact	-	0.0036	°C/W
T _{vj}	Virtual junction temperature			-40	125	°C
T _{OP} /T _{stg}	Operating junction/storage temperature range			-40	125	°C
-	Clamping force			33.0	37.0	kN

CHARACTERISTICS

T _j = 125°C unless stated otherwise						
Symbol	Parameter	Conditions	Min.	Max.	Units	
V_{TM}	On-state voltage	At 3000A peak, I _{G(ON)} = 8A d.c.	-	4.0	V	
I _{DM}	Peak off-state current	$V_{DRM} = 4500V, \ V_{RG} = 0V$	-	100	mA	
I _{RRM}	Peak reverse current	At V _{RRM}	-	50	mA	
V_{GT}	Gate trigger voltage	$V_{D} = 24V, I_{T} = 100A, T_{j} = 25^{\circ}C$	-	1.2	V	
l _{GT}	Gate trigger current	$V_D = 24V, I_T = 100A, T_j = 25^{\circ}C$	-	3.5	А	
I _{RGM}	Reverse gate cathode current	V _{RGM} = 16V, No gate/cathode resistor	-	50	mA	
E _{ON}	Turn-on energy	V _D = 2250V	-	3000	mJ	
t _d	Delay time	$I_{T} = 3000A$, $dI_{T}/dt = 300A/\mu s$	-	1.5	μs	
t _r	Rise time	I_{FG} = 40A, rise time < 1.0 μ s	-	3.0	μs	
E _{OFF}	Turn-off energy		-	6300	mJ	
t _{gs}	Storage time		-	20.6	μs	
t _{gf}	Fall time	$I_T = 3000A, V_{DM} = 3000V$	-	2.2	μs	
t _{gq}	Gate controlled turn-off time	Snubber Cap Cs = 6.0μF,	-	22.8	μs	
Q_{gQ}	Turn-off gate charge	$di_{GQ}/dt = 40A/\mu s$	-	10000	μС	
$Q_{_{\mathrm{GQT}}}$	Total turn-off gate charge		-	20000	μС	
I _{GQM}	Peak reverse gate current		-	830	А	

CURVES

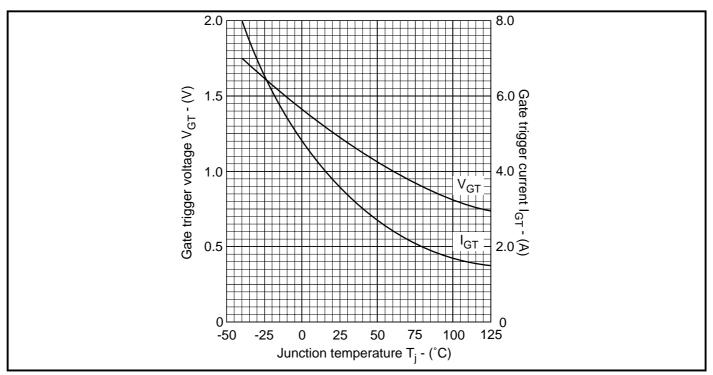


Fig.1 Maximum gate trigger voltage/current vs junction temperature

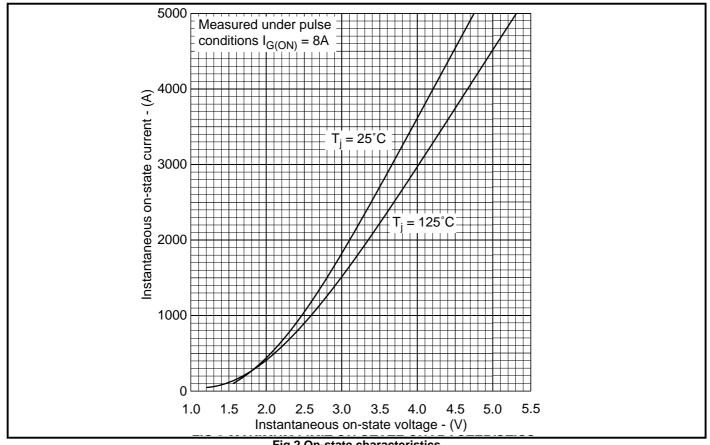


Fig.2 On-state characteristics

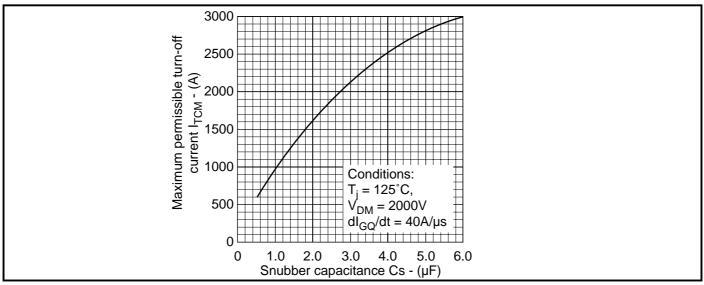


Fig.3 Maximum dependence of I_{TCM} on C_S

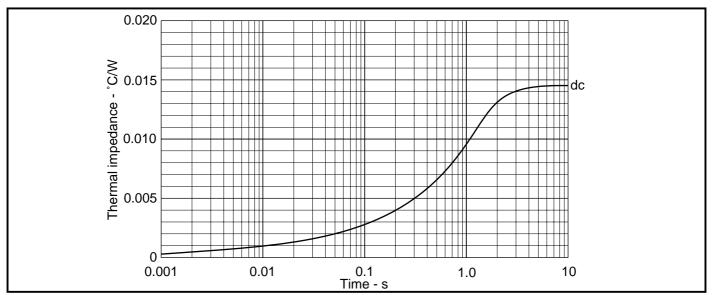


Fig.4 Maximum (limit) transient thermal impedance - double side cooled

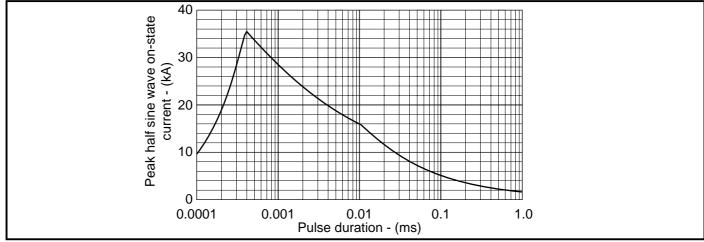


Fig.5 Surge (non-repetitive) on-state current vs time

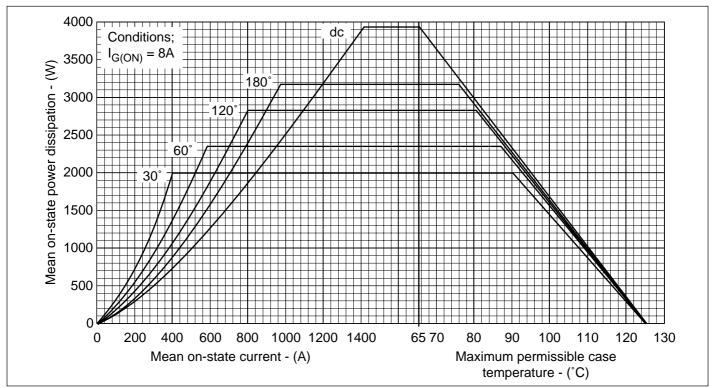


Fig.6 Steady state rectangluar wave conduction loss - double side cooled

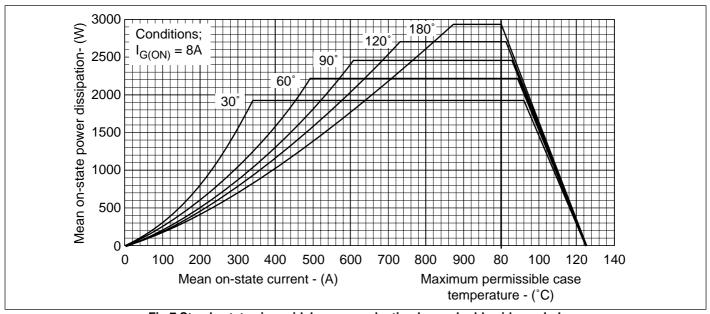


Fig.7 Steady state sinusoidal wave conduction loss - double side cooled

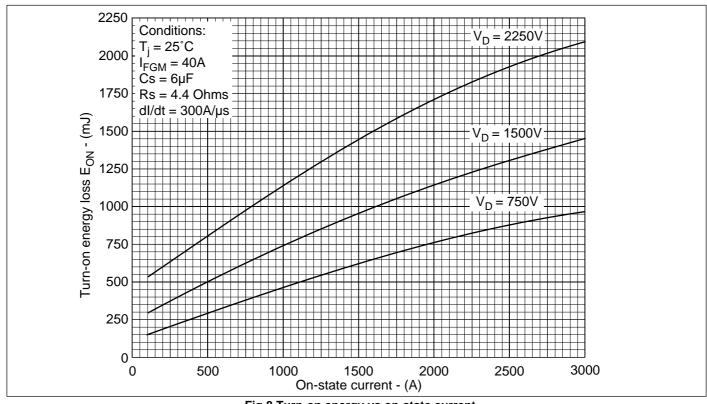


Fig.8 Turn-on energy vs on-state current

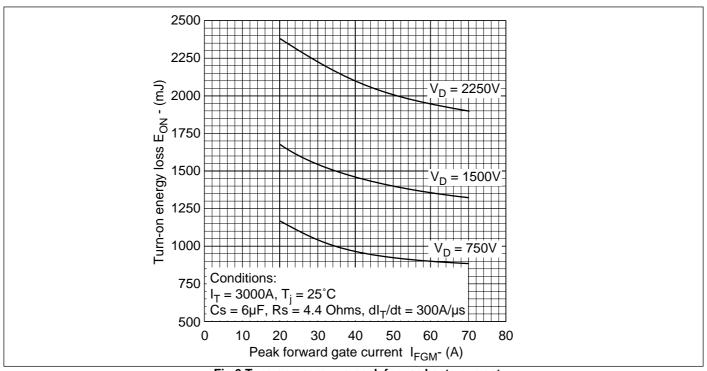


Fig.9 Turn-on energy vs peak forward gate current

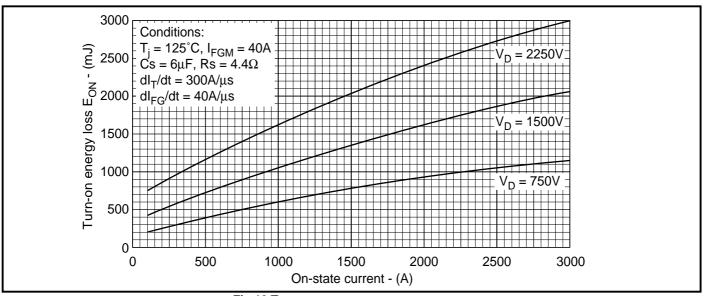


Fig.10 Turn-on energy vs on-state current

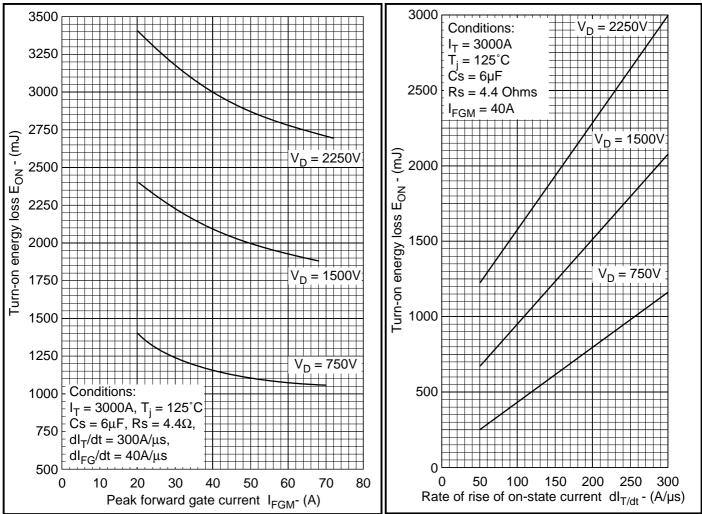


Fig.11 Turn-on energy vs peak forward gate current

Fig.12 Turn-on energy vs rate of rise of on-state current

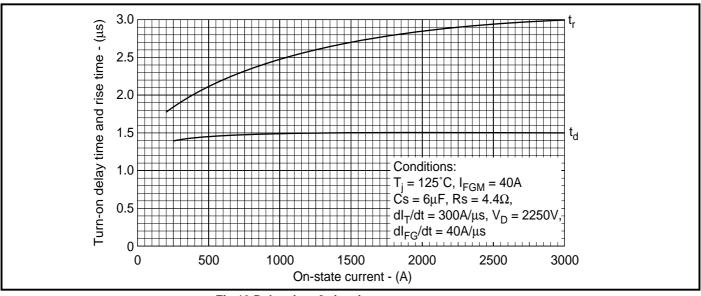


Fig.13 Delay time & rise time vs turn-on current

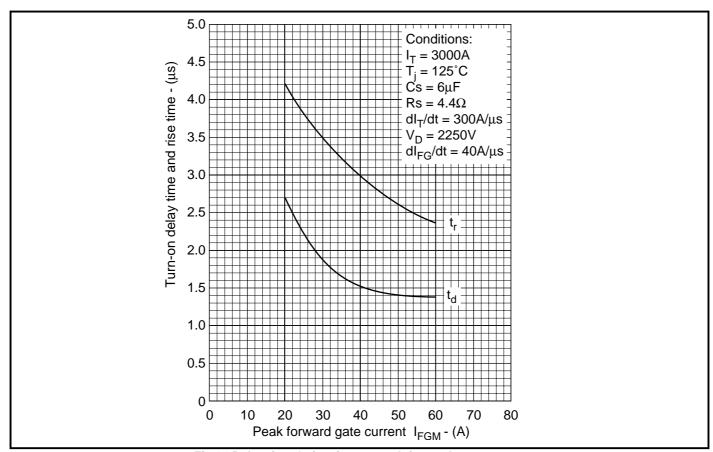


Fig.14 Delay time & rise time vs peak forward gate current

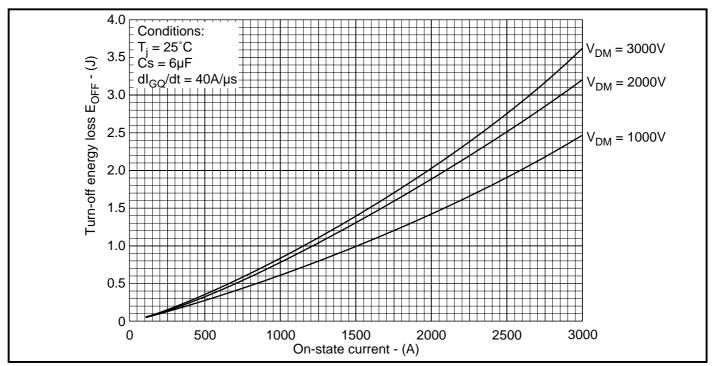


Fig.15 Turn-off energy vs on-state current

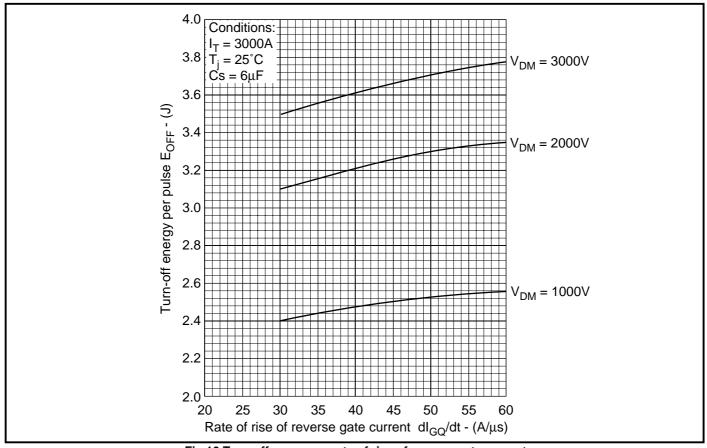


Fig.16 Turn-off energy vs rate of rise of reverse gate current

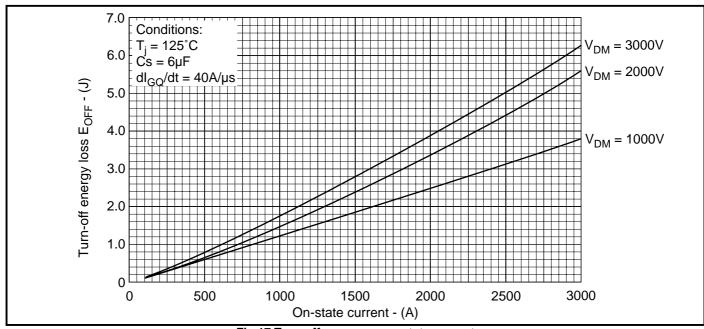


Fig.17 Turn-off energy vs on-state current

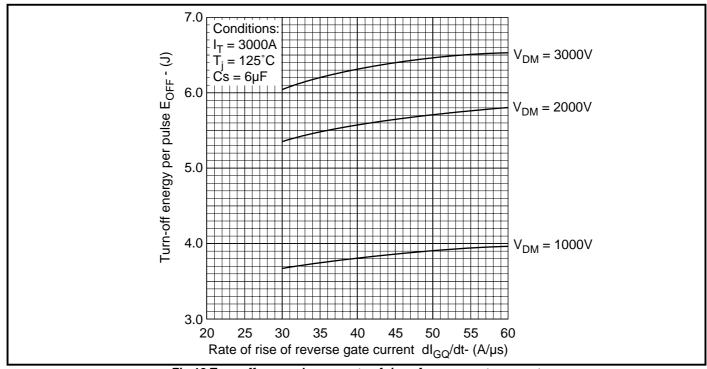


Fig.18 Turn-off energy loss vs rate of rise of reverse gate current

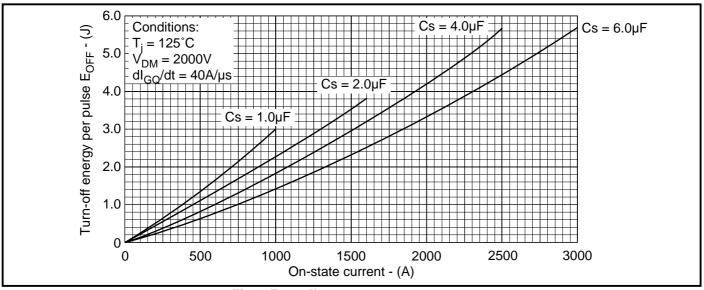


Fig.19 Turn-off energy vs on-state current

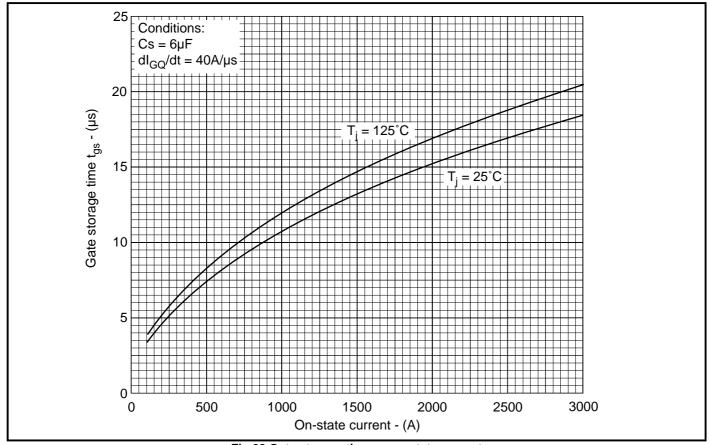


Fig.20 Gate storage time vs on-state current

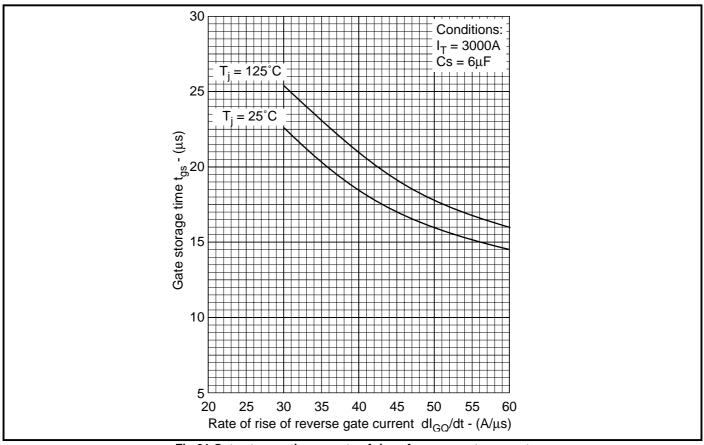


Fig.21 Gate storage time vs rate of rise of reverse gate current

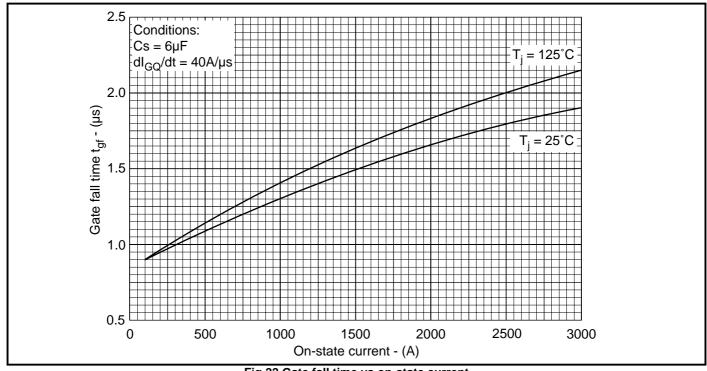


Fig.22 Gate fall time vs on-state current

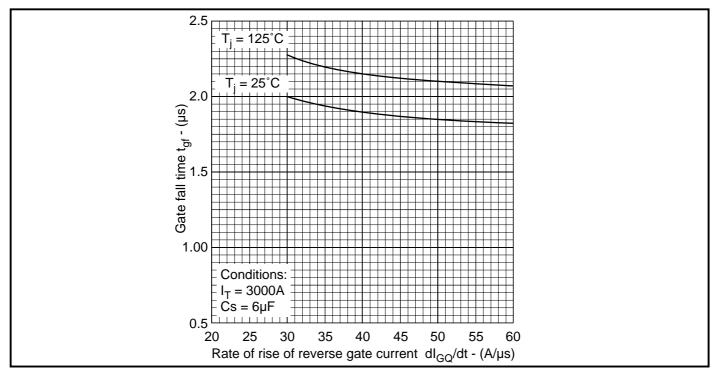


Fig.23 Gate fall time vs rate of rise of reverse gate current

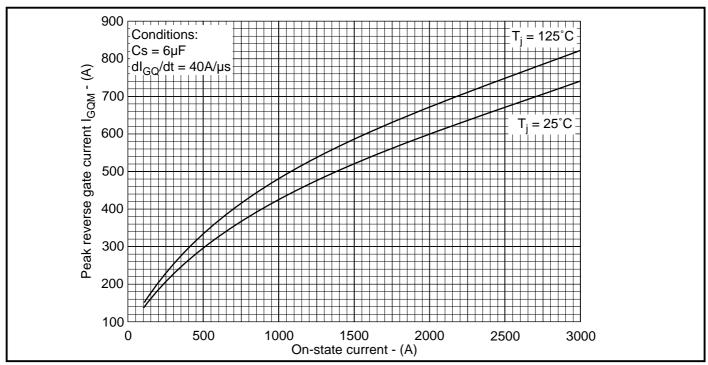


Fig.24 Peak reverse gate current vs turn-off current

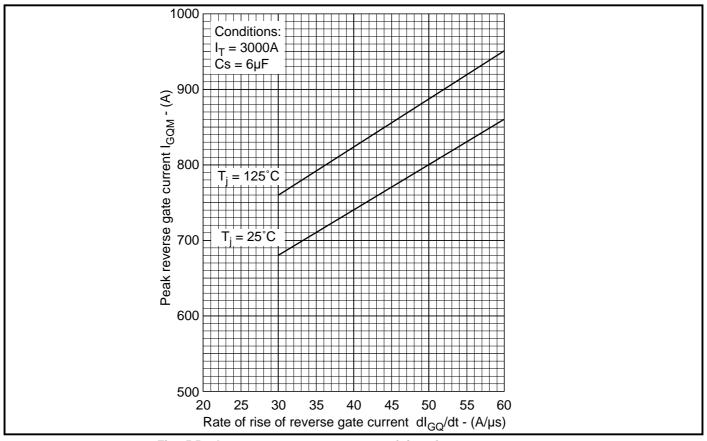


Fig.25 Peak reverse gate current vs rate of rise of reversegate current

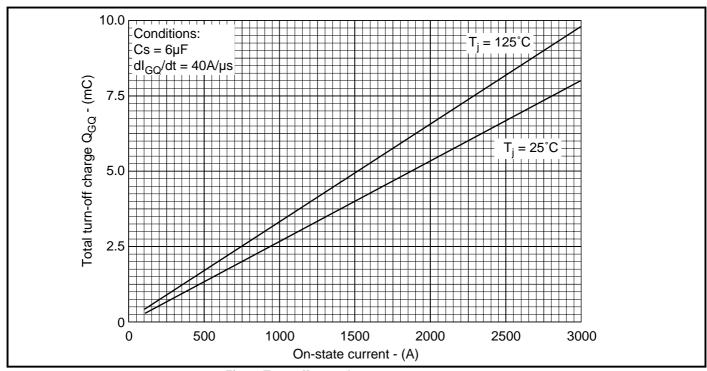


Fig.26 Turn-off gate charge vs on-state current

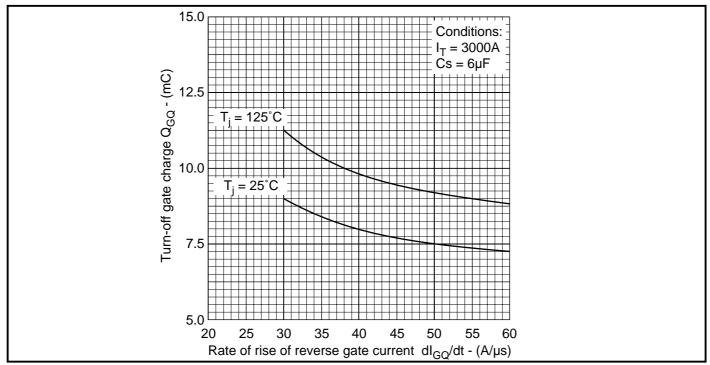


Fig.27 Turn-off gate charge vs rate of rise of reverse gate current

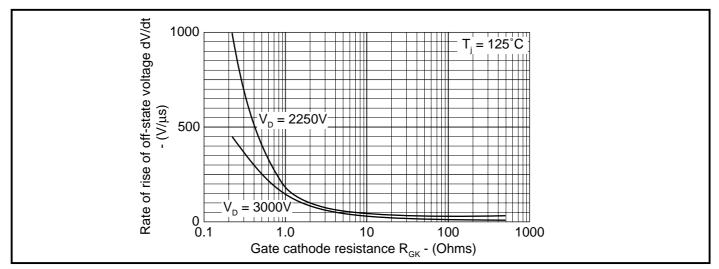


Fig.28 Rate of rise of off-state voltage vs gate cathode resistance

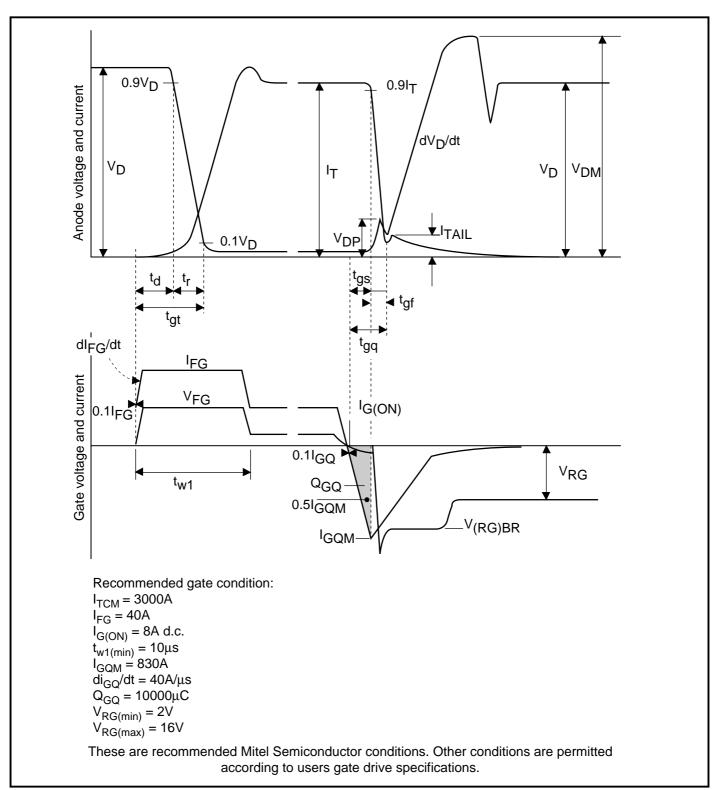
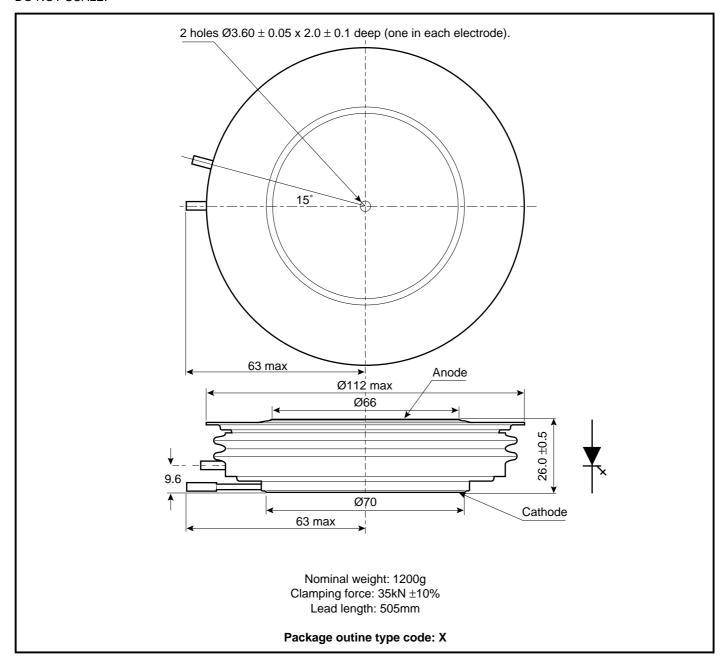


Fig.29 General switching waveforms

PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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